Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination
10/749,602	EMERY ET AL,
Examiner	Art Unit
Patricia Leith	1655

SEARCHED			
Class	Subclass	Date	Examiner
none			
	• .		
	•	-	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
		<u>, </u>	
		,	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST: JPO,EPO,DERWENT,USPATFULL,U SPGPUBS	6/30/2005	PL
STN: Indexed BIOSCIENCE cluster (74 databases)	6/30/2005	PL
Inventor name search PALM/EAST: JPO,EPO,DERWENT,USPATFULL,U SPGPUBS	7/21/2005	PL
Consulted parent case	7/20/2005	PL
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